

# Notices

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This section of the FEDERAL REGISTER contains documents other than rules or proposed rules that are applicable to the public. Notices of hearings and investigations, committee meetings, agency decisions and rulings, delegations of authority, filing of petitions and applications and agency statements of organization and functions are examples of documents appearing in this section.

## DEPARTMENT OF COMMERCE

### Foreign-Trade Zones Board

[Docket 70–2010]

#### Foreign-Trade Zone 158—Vicksburg/Jackson, MS; Application for Expansion

##### Correction

In notice document 2010–31877 beginning on page 79335 in the issue of Monday, December 20, 2010, make the following correction:

The subject is corrected to read as set forth above.

[FR Doc. C1–2010–31877 Filed 12–29–10; 8:45 am]

BILLING CODE 1505–01–P

## DEPARTMENT OF COMMERCE

### International Trade Administration

#### Application(s) for Duty-Free Entry of Scientific Instruments

Pursuant to Section 6(c) of the Educational, Scientific and Cultural Materials Importation Act of 1966 (Pub. L. 89–651, as amended by Pub. L. 106–36; 80 Stat. 897; 15 CFR part 301), we invite comments on the question of whether instruments of equivalent scientific value, for the purposes for which the instruments shown below are intended to be used, are being manufactured in the United States.

Comments must comply with 15 CFR 301.5(a)(3) and (4) of the regulations and be postmarked on or before January 19, 2011. Address written comments to Statutory Import Programs Staff, Room 3720, U.S. Department of Commerce, Washington, DC 20230. Applications may be examined between 8:30 a.m. and 5 p.m. at the U.S. Department of Commerce in Room 3720.

*Docket Number:* 10–067. *Applicant:* University of Chicago, Argonne LLC, 9700 South Cass Ave., Lemont, IL 60439. *Instrument:* Pilatus 100K Pixel

Detector System. *Manufacturer:* Dectris Ltd., Switzerland. *Intended Use:* The instrument will be used to study Small-Angle X-ray Scattering (SAXS) for chemical, biological, and materials science, time resolved diffraction, and x-ray surface diffraction for magnetic materials. The instrument is the first and only commercially available pixel array detector for x-ray applications. The instrument's unique capabilities are a high detection efficiency (no readout noise and direct detection scheme), high dynamic range (20-bits), and fast readout speeds. *Justification for Duty-Free Entry:* There are no instruments of the same general category being manufactured in the United States. *Application accepted by Commissioner of Customs:* December 6, 2010.

*Docket Number:* 10–068. *Applicant:* University of Chicago, Argonne LLC, 9700 South Cass Ave., Lemont, IL 60439. *Instrument:* Pilatus 300K Pixel Detector System. *Manufacturer:* Dectris Ltd., Switzerland. *Intended Use:* The instrument will be used for wide angle SAXS, involving biological systems (proteins, RNA, DNA), catalysis reactions, and soft-condensed matter physics (e.g., ordering of polymers and colloidal suspensions). The instrument's unique capabilities are a high detection efficiency (no readout noise and direct detection scheme), high dynamic range (20-bits), and fast readout speeds. *Justification for Duty-Free Entry:* There are no instruments of the same general category being manufactured in the United States. *Application accepted by Commissioner of Customs:* December 6, 2010.

*Docket Number:* 10–069. *Applicant:* University of Minnesota School of Dentistry, 6–150 MoosT, 515 Delaware St., S E, Minneapolis, MN 55455. *Instrument:* Dental Imaging System: Cross-Polarization Swept-Source Optical Coherence Tomography with a MEMS Handpiece. *Manufacturer:* Santec Corporation, Japan. *Intended Use:* The main use for the instrument is to study the oral biofilm of dental decay in children. This custom made imaging system will image under resin composite dental fillings. The three crucial aspects of the instrument are size (the hand piece is 16 X 15 X 80 mm), speed (can operate at 30 kHz swept source speed), and image contrast (able to suppress the parallel polarization by 30 dB). *Justification for*

*Duty-Free Entry:* There are no instruments of the same general category being manufactured in the United States. *Application accepted by Commissioner of Customs:* December 8, 2010.

Dated: December 22, 2010.

#### Gregory Campbell,

Director, IA Subsidies Enforcement Office.

[FR Doc. 2010–32934 Filed 12–29–10; 8:45 am]

BILLING CODE 3510–DS–P

## DEPARTMENT OF COMMERCE

### International Trade Administration

#### Vanderbilt University, et al.; Notice of Consolidated Decision on Applications for Duty-Free Entry of Electron Microscopes

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89–651, as amended by Pub. L. 106–36; 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5 p.m. in Room 3720, U.S. Department of Commerce, 14th and Constitution Avenue, NW., Washington, DC.

*Docket Number:* 10–065. *Applicant:* Vanderbilt University, Nashville, TN 37235. *Instrument:* Electron Microscope. *Manufacturer:* FEI Company, Czech Republic. *Intended Use:* See notice at 75 FR 73034, November 29, 2010.

*Docket Number:* 10–066. *Applicant:* Vanderbilt University, Nashville, TN 37235. *Instrument:* Electron Microscope. *Manufacturer:* JEOL Limited, Japan. *Intended Use:* See notice at 75 FR 73034, November 29, 2010.

*Comments:* None received. *Decision:* Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as these instruments are intended to be used, was being manufactured in the United States at the time the instruments were ordered. *Reasons:* Each foreign instrument is an electron microscope and is intended for research or scientific educational uses requiring an electron microscope. We know of no electron microscope, or any other instrument suited to these purposes, which was being manufactured in the United States at the time of order of each instrument.